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Docket No. YOR920040080US1 (YOR.517)

AMENDMENTS TO THE CLAIMS:

1. (Currently amended) A coplanar waveguide (CPW) probe assembly, comprising:

at least one center probe element, each having a respective center probe contact point;

and

at least one peripheral probe element, each having a respective peripheral contact point,

wherein a pitch of said at least one center contact and said at least one peripheral contact is adjustable, a physical separation between said at least one center contact and said at least one peripheral contact is controlled by a longitudinal translation of a movable sleeve fitted to an outer wall of said CPW probe assembly and an electrical impedance of said probe is substantially independent of said pitch a calibration indication is associated with a position of said movable sleeve.

2. (Canceled)

3. (Original) The CPW probe assembly of claim 1, further comprising:

a spreader for urging said at least one peripheral probe element apart from said at least one center probe element.

4. (Original) The CPW probe assembly of claim 1, further comprising:

a shorting device that maintains an electrical contact between said at least one peripheral contact and an outer wall of said CPW probe as said pitch changes.

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5. (Currently amended) The CPW probe assembly of claim 2 1, wherein said movable sleeve is fitted to said outer wall as a threaded mechanism.

6. (Canceled)

7. (Original) The CPW probe assembly of claim 4, wherein said shorting device comprises a conductive material in a compressed state that urges said at least one peripheral probe element apart from said at least one center probe element.

8. (Original) The CPW probe assembly of claim 7, wherein said shorting device comprises a metal spring.

9. (Currently amended) A test probe assembly comprising:

a micro-coaxial cable having at least one center conductor and a conductive outer wall;
and

a probe tip section comprising at least one center contact, each respectively extending from one of said at least one center conductor, and at least one peripheral contact, each electrically connected to said conductive outer wall at a predetermined distance from an end of said conductive outer wall in a manner to provide a flexure between the peripheral contact and said conductive outer wall, wherein a pitch between said at least one center contact and said at least one peripheral contact is being adjustable because of said flexure;

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a sleeve that is longitudinally movable along said outer wall, each said at least one peripheral contact being attached to said outer wall such that a longitudinal movement of said sleeve causes said adjustable pitch; and

a calibration scale on said outer wall to provide an indication of a value of said pitch based on a position of said sleeve.

10. (Original) The test probe assembly of claim 9, wherein said probe is operable over a microwave range of wavelengths.

11. (Canceled)

12. (Currently amended) The test probe assembly of claim 11, wherein said outer wall incorporates a threaded interface and said sleeve includes an inner thread that engages therewith.

13. (Original) The test probe assembly of claim 9, further comprising:

a shorting device that maintains an electrical contact between said at least one peripheral contact and said outer wall substantially adjacent to where said at least one peripheral contact contacts a device under test.

14. (Original) The test probe assembly of claim 13, wherein said shorting device comprises a spreader that urges said at least one peripheral contact away from said at least one center contact.

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15. (Original) The test probe assembly of claim 14, wherein said spreader comprises a metal spring.

16. (Currently amended) The test probe assembly of claim ~~14~~ 9, wherein said at least one peripheral contact is shaped to provide a taper so that said longitudinal movement of said sleeve compresses said at least one peripheral contact by moving along said taper shape.

17-25. (Canceled)

26. (Previously presented) The test probe assembly of claim 9, wherein each said at least one peripheral contact is affixed to said conductive outer wall in a substantially permanent manner.